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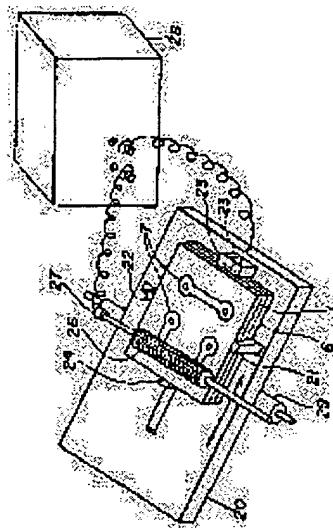
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## (54) TESTING APPARATUS OF WITHSTAND VOLTAGE OF PRINTED CIRCUIT BOARD

## (57) Abstract:

PURPOSE: To realize a test fit for different kinds of circuit patterns or circuit boards by providing a testing terminal in touch with a metallic plate, a conductive roller rotating in touch with a circuit pattern, and a voltage-resistance checking circuit between said testing terminal and roller.

CONSTITUTION: Fixed pins 21, 22 for holding a substrate 6 therebetween and, a testing terminal 23 and a movable pin 24 for holding the substrate therebetween at right angles to the fixed pins 21, 22 are all projected on the upper surface of a holding bed 20 to set the terminal 23 at such a height that an end of the terminal 23 is in touch with a metallic plate 1. A negative voltage of a checking circuit 28 is led to a conductive roller 26 via a slip ring 27, while a positive voltage is led to the terminal 23. When the bed 20 with the substrate 6 mounted thereon is inserted between the rollers 26, 29 while the roller 26 is brought into contact with a circuit pattern 7, the negative voltage is led to the pattern 7. Accordingly, the resistance to voltage between the circuit pattern 7 and the metallic plate 1 to which the positive voltage is led from the terminal 23 is checked. Therefore, even the circuit patterns and printed circuit boards of different size can be checked by the same apparatus without changing the apparatus in a simple manner with high efficiency.



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